**XIV SuperB General Meeting** 

### Update on pixel bus and pixel module interfaces

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On behalf of INFN Milano and Università degli Studi di Milano





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# Understanding "prototype bus" construction

- Three main concerns:
- Bus designed for 50 Ohm Impedance
- Measured impedance is > 60 Ohm
- Impedance changes between identical lines
- Measured NEXT crosstalk (~ 10%) much higher than simulated (3%)





mpedance (Ohm)



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# Understanding "prototype bus" construction

• Stack-up by design

Number of layers: 8 Total thickness = 156 um



NN	Layer Name	Туре	Usage	Thickness um	Er
1	TOP-LAYER	Metal	Signal	13	<auto></auto>
2	Polyimide	Dielectric	Substrate	15	3.5
З	Glue	Dielectric	Substrate	5	4.5
4	INNER-LAYER	Metal	Signal	13	<auto></auto>
5	Polyimide	Dielectric	Substrate	40	3.5
6	Glue	Dielectric	Substrate	5	4.5
7	GROUND-PLANE	Metal	Plane	50	<auto></auto>
8	Polyimide	Dielectric	Solder Mask	15	3.5





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### Analysis of the stack-up



Thanks to F. Bosi and INFN Pisa



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### What we understood so far

### • Impedance

- Impedance is obtained by increasing glue thickness and NOT by thicker kapton layers
  - *E*r is different for glue and kapton, dielectric thickness is more  $\rightarrow Z$  moves toward the right value, not exact value yet !!
  - Layer thickness must be carefully measured during stack-up
  - » It will be good practice to measure thickness at each step in production
  - » The kapton layer is always the same (nominal thickness is 12.5 um)
- Aluminum signal lines are slightly thicker than expected
- Trace widht is ~ 75 um, but with some "undercut" due to etching. Trace width could be not uniform  $\rightarrow$  it will explain impedance variation from line to line.
- Power planes are "polished" before depositing the glue  $\rightarrow$  the effective thickness must be considered for power drop calculation. Thicker planes (50 um or more) can be used but not available at all time.
- Crosstalk
  - Not yet understood the extra crosstalk  $\rightarrow$  solder mask properly considered ?
  - We need more cut-out of the bus to evaluate the top metal layer
    - Thanks to Pisa help we will have the info soon

# **Bus for a 3-chip assembly**

### Layout of a BUS for up to 3 modules

- using front-end IC "FE 32x128" (expected in the summer)
- Bus widht: 8.7 mm
- Signal trace layer widht: 75 µm
- Bus length  $\sim 6.5$  cm



### Issues discussed with CERN:

- "Area opening" of  $300x500 \ \mu m$  possible on power planes to allow decoupling (cap mounting). Openings will be gold-nickel plated
- Bonding pads will be aluminum. Avoid bimetallic junctions to increase reliability
- Use mesh instead of full layer for power and ground planes  $\rightarrow$  better for X<sub>0</sub>



# Bus for a 3-chip assembly

### Other important design guidelines:

- Each chip will have its own signal data layer
  - 3 chips  $\rightarrow$  3 layers
  - Same impedance on each data layer (~ 50 Ω, 75 Ω under study)
- Two signal layers are striplines (to decrase crosstalk) the other lines are microstrip (to study two options)
- To decrease layout complexity no vias will be used
- 3 power planes + 3 ground planes
  - 2 digital power/ground kept separated to avoid possible interferences
- Data bus layout have been designed to reduce inter-bus capacitive values
- Upgrade to 6 chips will scale accordingly
  - Same number of layers





## Signal layers for the 3-chip BUS



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### Stack-up modification (50 $\Omega$ )



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100		1	1	//r	21 um
				W	——— 12 um
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Giue				∥ <i>ŗ</i> −−−−−	25 um
Clue			///	(/	——————————————————————————————————————
				V/	12 um
Glug				[	——————————————————————————————————————
Kapton					——— 25 um
Glue					50.um
					50 um
Addite					——— 12 um
Glue					50 um
Kapton —					
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Glue					50 um
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Glue				<u></u>	25 um
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Kenton					15 um
Glue					50
SIGNALS-3					——— 12 um
Glue					50 um
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### **New situation**

- **Overall thickness increases** 
  - Due to striplines  $\rightarrow$  overall thickness ~ 800 um
  - Minimal glue thickness (5 um) used only between planes
  - Mesh plane structure (70/30 full/empty) compensate material on average
- Avoiding vias
  - Each layer is prepared and tested independently
  - Stack-up assembled at the last moment  $\rightarrow$  no vacuum deposition
  - No minimum quantity
    - Consider to submit two design versions for comparison
- Redesign status
  - Simulation of new layout will be completed by mid October
  - Bonding layout should be reviewed
    - Bonding pads are not on the uppermost layers anymore
- **Production schedule** 
  - Design/s submitted October  $\rightarrow$  BUS back by end of March '11



### 3D Model of the assembly







## HDI, transition card development

- Transfer data from layer0 front-end electronics to DAQ
  - to collect data and program FSSR2 (baseline) or MAPS (upgrade)
  - to store data for 20 µs by means of buffers (hypothesis)
  - to increase robustness using ECC codes and radiation hardening by design ASICs
  - to transfer data at high frequencies (up to 5 Gbps)
  - to re-use similar approach for others layers (with less contraints)



### **Present Understanding**

- At high occupancy (layer 0), FSSR2s are not able to collect data properly
- A triggered solution needs to be implemented in the FSSR2 chips
- For this reason our test/development strategy has moved to a data push-out solution



### Main strategy

 Usage of a rad-hard IC containing data organizer, buffers, and serializer



HDI size  $\approx$  1.0 TH x 14.8 W x 70 L mm Copper tail size  $\approx$  500 L mm  $\rightarrow$  ( $\approx$  16 lines) **PIX/MAPS:** Kapton/aluminum bus size  $\approx$  0.3 TH x 20 W x 45 L mm  $\rightarrow$  ( $\approx$  100 lines)



# HDI prototype

- We have developed a first prototype using a Virtex 5 FPGA
  - Prototype contains:
    - Differential receivers
    - **De-serializer**
    - Data organizer





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# Test of the FPGA prototype

- Extensive tests demonstrate that the Virtex 5 FPGA prototype works as expected
  - A C++ program generates data as an FSSR2 will do and data stream is loaded in a Logic State Analyzer (LSA)
  - Such data are then emulated by means of the pattern generator of the LSA
  - The prototype can accept 1,2,6 differential input line
  - The prototype is able to lock on the sync word
  - Data are handled (deserialized, buffered) by the FPGA before sending them back to the LSA for comparison



### **Next Steps**

- Study data transmission using the prototype BUS
  - Data sent from the LSA pattern generator through to the FPGA via the BUS lines (differentiall and not)
  - Signal integrity measurements and comparison with simulation
  - Multiple line inejction to study crosstalk and jitter
- Rad hard Serializer (LOC) 16:1, 5 GBps
  - ITER export limitation solved
  - Dallas chip expected in the coming weeks
  - LOC will be used instead of FPGA rocketIO



